

**A new approach to build a low-level malicious fault list starting from high-level description and alternative graphs**  
Benso, A.; Prinetto, Paolo; Rebaudengo, M.; Sonza, M.; **Ubar, Raimund-Johannes** Proceedings IEEE European Design & Test Conference, Paris, March 17-20, 1997 1997 / p. 560-565 <https://ieeexplore.ieee.org/document/582417>